



U.S. Department of Commerce Patent and Trademark Office					ATTY DOCKET NO.	SERIAL NO.	
					BMID 9958 CIP US		10/601,144
					APPLICANT BHULLAR et al.		
INFORMATION DISCLOSURE STATEMENT					FILING DATE	GROUP	
06/20/2003		1243 3700					
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date
cg	1	4,081,653	3-28-1978	Koo et al.	219	121	
	2	4,131,484	12-26-78	Caruso, et al.	134	1	
	3	4,414,059	11-8-83	Blum et al.	156	659.1	
	4	4,684,437	8-4-1987	Donelon et al.	156	643	
	5	4,865,873	9-12-1989	Cole et al.	427	53.1	
	6	4,874,500	10-17-89	Madou et al.	204	412	
	7	4,897,173	1-30-90	Nankai et al.	204	403	
	8	5,018,164	5/21/91	Brewer et al.	372	109	
	9	5,089,103	2-18-92	Swedberg	204	182.8	
	10	5,104,480	4-14-92	Wojnarowski et al.	156	643	
	11	5,120,420	6-9-92	Nankai et al.	204	403	
	12	5,264,103	11/93	Yoshioka et al.	204	403	
	13	5,266,179	11-30-93	Nankai et al.	204	401	
	14	5,288,636	2-22-94	Pollmann et al.	435	288	
	15	5,334,279	8-2-94	Gregoire	156	630	
	16	5,336,388	8-9-94	Leader et al.	204	406	
	17	5,382,346	1-17-95	Uenoyama et al.	204	403	
	18	5,390,412	2-21-95	Gregoire	29	848	
	19	5,391,250	2-21-95	Cheney II et al.	156	268	
	20	5,395,504	3-7-95	Saurer et al.	204	403	
	21	5,413,690	5-9-95	Kost et al.	204	403	
	22	5,414,224	5-9-95	Adasko et al.	174	262	
	23	5,426,850	6-27-95	Fukutomi et al.	29	848	
	24	5,437,999	5-13-97	Diebold et al.	435	288	
	25	5,451,722	9-19-95	Gregoire	174	261	
	26	5,465,480	11-14-95	Karl et al.	29	825	
	27	5,496,453	3-5-96	Uenoyama et al.	205	777.5	
	28	5,508,171	4-16-96	Walling et al.	205	777.5	
	29	5,509,410	4-23-96	Hill et al.	128	637	
	30	5,512,489	04-1996	Girault et al.	205	777.5	
	31	5,575,930	11-19-96	Tietje-Girault et al.	216	65	
	32	5,576,073	11-19-96	Kickelhain	427	555	
	33	5,589,326	12-31-96	Deng et al.	435	4	
	34	5,593,739	1-14-97	Kickelhain	427	555	
	35	5,628,890	5-13-97	Carter et al.	204	403	
	36	5,635,054	06-1997	Girault et al.	205	775	
	37	5,682,884	11-4-97	Hill et al.	128	637	
	38	5,708,247	1-13-98	McAleer et al.	204	403	
	39	5,735,953	5-26-98	Henning et al.	205	778	
	40	5,773,319	6-30-98	Chu et al.	438	39	
	41	5,739,039	04-1998	Girault et al.	436	149	
	42	5,758,398	6-2-98	Rijnbeek et al	29	25.42	
	43	5,759,364	6-2-98	Charlton et al.	204	403	
	44	5,762,770	6-9-98	Pritchard et al.	204	403	
	45	5,798,031	8-25-98	Charlton et al.	204	403	
	46	5,948,289	09-07-99	Noda et al.	219	121.69	
	47	5,955,179	9/99	Kickelhain et al.	428	210	
cg	48	5,956,572	9-21-99	Kidoguchi et al.	438	96	
Examiner <i>Gales</i>					Date Considered <i>11/17/05</i>		

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				APPLICANT BHULLAR et al.			
				FILING DATE 06/20/2003	GROUP 1743 37 ac		
INFORMATION DISCLOSURE STATEMENT							

*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date
gja	5,965,001	10-12-99	Chow et al.	204	600	
gja	6,004,441	12-21-99	Fujiwara et al.	204	412	
gja	6,103,033	8-15-00	Say et al.	156	73.1	
gja	6,134,461	10-17-00	Say et al.	600	345	
gja	6,165,594	12-26-00	Moh et al.	428	207	
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gja	6,203,952 B1	3-20-01	O'Brien et al.	430	17	
gja	6,258,229 B1	7-01	Winarta et al.	205	403	
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gja	6,309,526 B1	10-30-01	Fujiwara et al.	204	403	
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gja	US 2003/0088166 A1	5-8-2003	Say et al.			11-11-2002

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gja	0 480 703 B1	3/97	EP			--
gja	0 875 754	11-4-98	EP			--
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gja	1 195 441 A1	4-10-02	EP			--
gja	1 202 060 A1	5-2-2002	EP			--
gja	1 203 956 A2/A3	5-8-2002	EP			--
gja	1 288 654 A1	03-05-03	EP			--
gja	2000-121594 abstract	April 00	JP			--
gja	56100451	Aug 81	JP			yes (abstract)
gja	11297890	Oct. 99	JP			yes (abstract)
gja	7-66499	3-10-95	JP			yes (abstract)
gja	7-290751	11-7-95	JP			yes (abstract)
gja	9-260697	10-3-97	JP			yes (abstract)
gja	10-241992 abstract	9-1-98	JP			--
gja	10-303444 abstract	11-1-98	JP			--
gja	10-275959	10-1-98	JP			--
gja	5-31 5703	11-26-93	JP			yes (abstract)
gja	10-52780 abstract	2-24-98	JP			yes (abstract)
Examiner	c.j. Arles		Date Considered	16/7/05		

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		APPLICANT BHULLAR et al.	
		FILING DATE 06/20/2003	GROUP <i>1745-3700</i>
<b>INFORMATION DISCLOSURE STATEMENT</b>			
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)			
<i>CJA</i>	116	LPKF MicrolineLaser II, LPKF Laser & Electronics AG; LPKF; Art.-Nr. 107645-2 (01/00) (2pp.)	
<i>CJA</i>	117	Microline Solutions, LPKF Laser & Electronics AG; LPKF; Art.-Nr. 107658-1 (01/00) (3pp.)	
Examiner <i>Oganes</i>		Date Considered <i>11/7/05</i>	

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					APPLICANT BHULLAR et al.	FILING DATE 06/20/2003
INFORMATION DISCLOSURE STATEMENT					FOREIGN PATENT DOCUMENTS	
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	87	WO 91/08474	6-13-91	PCT		--
	88	WO 95/22881	8-24-95	PCT		--
	89	WO 98/35225	8-13-98	PCT		--
	90	WO 98/49773	Dec 98	PCT		--
	91	WO 99/13101	3-18-99	PCT		--
	92	WO 99/30152	6-17-99	PCT		--
	93	WO 99/45387	9-10-99	PCT		--
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	95	WO 00/42472 A1	7-20-00	PCT		--
	96	WO 00/73778	12/2000	PCT		--
	97	WO 00/73785	12/2000	PCT		--
	98	WO 01/36953	5-25-01	PCT		yes abstract
	99	WO 01/75438	10-11-01	PCT		--
	100	WO 01/25775	4-12-01	PCT		--
	101	WO 01/92884	12-6-01	PCT		yes abstract
	102	WO 02/086483	10-31-02	PCT		yes abstract
	103	WO 02/27074	4-4-02	PCT		yes abstract
	104	WO 02/086483	10/2002	PCT		yes abstract
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*Examiner Initial	105	Tender, L. et al., "Electrochemical Patterning of Self-Assembled Monolayers onto Microscopic Arrays of Gold Electrodes Fabricated by Laser Ablation, <i>Langmuir</i> , 1996, 12, 5515-5518.				
	106	Tahhan, Isam, "Biocompatible Microstructuring of Polymers and Electrodes with an Excimer Laser", MEDICS Workshop 2000 Speakers Abstracts, 2 pp.				
	107	Sheppard, Jr. et al. "Electrical Conductivity Measurements Using Microfabricated Interdigitated Electrodes", <i>Anal. Chem.</i> , 1993, 65, 1199-1202.				
	108	Srinivasan R., et al. "Ultraviolet Laser Ablation of Organic Polymers", <i>Chem. Rev.</i> , 1989, 89, 1303-1316.				
	109	Zongyi, Q., et al. "Excimer Laser Patterning on Thin Polymer Surfaces for Electrochemical Gas Sensors", Polymer Physics Laboratory, Changchun Institute of Applied Chemistry, Chinese Academy of Sciences, Changchun, Peop. Rep. China., Proceedings of the International Conference on Lasers (1999) 21 <sup>a</sup> (Abstract) 1pp.				
	111	Vaucher et al. "Laser Direct Imaging and Structuring: An Update", <a href="http://www.circuitree.com/CDA/ArticleInformation/features/BNP_Features_Item/0.21_31.81173.00.html">http://www.circuitree.com/CDA/ArticleInformation/features/BNP_Features_Item/0.21_31.81173.00.html</a> ; posted on: 08/01/2002.				
	112	Wu, J. et al. "Single-shot Excimer Laser Ablation of Thick Polymer Resists on Metallic Substrates", AMP Journal of Technology VOL 1 November, 1991, 69-79.				
	113	Srinivasan, R., "Ablation of Polymers and Biological Tissue by Ultraviolet Lasers", <i>Science</i> , Vol. 234, October 21, 1986, 559-564.				
	114	Colon, W., "Microanalysis: Biosensors at the Point of Care", MST News 01/04, pages 9-11.				
	115	Duley, W.W. "UV Lasers: effects and applications in materials science", Chapter 3 Photochemical and photothermal effects, Cambridge University Press, pages 78-97.				
Examiner	C.J. Culver			Date Considered	15/11/05	
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## **INFORMATION DISCLOSURE STATEMENT BY APPLICANT**

*(use as many sheets as necessary)*

Sheet 1 of 1

Substitute for form 1449A/PTO				Complete if Known	
<b>INFORMATION DISCLOSURE STATEMENT BY APPLICANT</b>				Application Number	10/601,144
(use as many sheets as necessary)				Filing Date	20-Jun-03
				First Named Inventor	Bhullar
				Group Art Unit	Unknown
				Examiner Name	Unknown CARL J. Arbes
Sheet	1	of	1	Attorney Docket Number	
				BMID 9958 CIP	

**U.S. PATENT DOCUMENTS**

Examiner Initials*	Cite No.*	Foreign Patent Document	Publication Date MM-DD-YYYY	Name of Patentee or Application of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T*
		Country Code* Number* Kind Code* (if known)				
04	1	JP 189675 (abstract)	1997-04-22	Matsushita Electric Ind Co. Ltd..		X

Examiner Signature		Date Considered	11/17/05
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